

Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D
Characterisation and Imaging with Ion Beams | (smr 2856)

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3D Characterization with MEIS

Tuesday, 27 September 2016 12:00 (1:00)

Content

Examples of the use of MEIS for the characterization of nanostructured materials through the software PowerMeis will be given. Some illustrative examples will be shown in this talk namely, characterization of Au and core-shell NPs exposed on the surface, system of buried NPs synthesized by ion implantation, swift-heavy ion-sputtered CaF₂ nanoparticles, and finally trench arrays used to build 3D transistors.

Summary

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Session Classification : DAY 2